


<b>Search Notes</b>  	<b>Application/Control No.</b>  10537069	<b>Applicant(s)/Patent Under Reexamination</b>  COLLINS ET AL.
	<b>Examiner</b>  HENG M CHAN	<b>Art Unit</b>  4181

SEARCHED			
Class	Subclass	Date	Examiner
423	417	12/01/2008	/HMC/
423	supplemented with text	12/01/2008	/HMC/

SEARCH NOTES		
Search Notes	Date	Examiner
EAST databases: USPAT, USPG-PUB, JPO, EPO, USOCR, FPRS, DERWENT, IBM_TDB	12/01/2008	/HMC/
Inventors searched in Palm	11/26/2008	/HMC/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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